

Design, Automation and Test in Europe (DATE) Conference 2016

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In March 2016, I visited the DATE conference with the poster presentation titled “A synthesis-agnostic behavioral fault model for high gate-level fault coverage”. The DATE conference and exhibition is the main European event bringing together designers and design automation users, researchers and vendors, as well as specialists in the hardware and software design, test and manufacturing of electronic circuits and systems. This is the world’s second most important event in this domain, after Design Automation Conference.

The conference was 5 days long, with the first day dedicated to tutorials and the co-located workshops took place at the last day. During the second to fourth days, the main technical program was held. A large conference, such as DATE, usually tries to cover all of relevant subtopics, however, this year a slight emphasis towards an emerging topic of Internet of Things – small low-power low-cost devices with ability to sense the real world and exchange data – was noticeable.

Poster presentations generally provide an opportunity to meet the domain experts in live face-to-face discussions, which I used, making several contacts with people from both academia and industry and getting a valuable feedback about my research.